OPTICAL WAFER SORTING

For Diffractive Optical Elements (DOE)

Alfamation system platform for high volume micro-optics testing it's based on a high-end wafer handling system with flexible architecture.

Equipped with an Optical Analysis Group specifically designed for diffractive optical elements characterization.

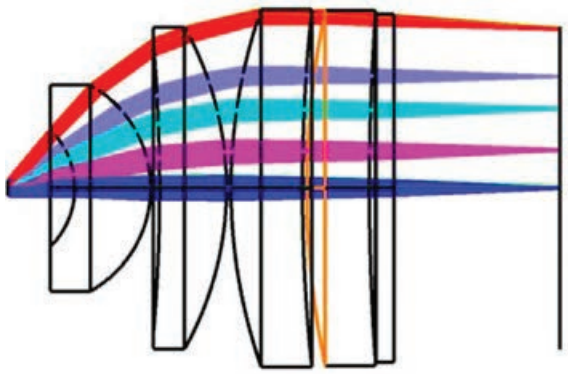
Based on a custom conoscope-like relay lens, implements a direct projection of the DOE pattern on to a high resolution sensor gaining uncommitted sensitivity and angular resolution.

A diffraction controlled beam shaper permits to stimulate device in the optimal way.

KEY FEATURES AND BENEFITS

- Very High resolution and sensitivity
- Mass production approach
- High repeatability wafer handler equipped with:
  - Wafer warpage compensation system
  - Alignment tools
  - Automated visual inspection system
  - Barcode/OCR reading system
- Cleanroom compatibility
- Optimized footprint
- According to CE/UL safety standards

Ultra High FOV relay lens scheme sample



TECHNICAL SPECIFICATIONS

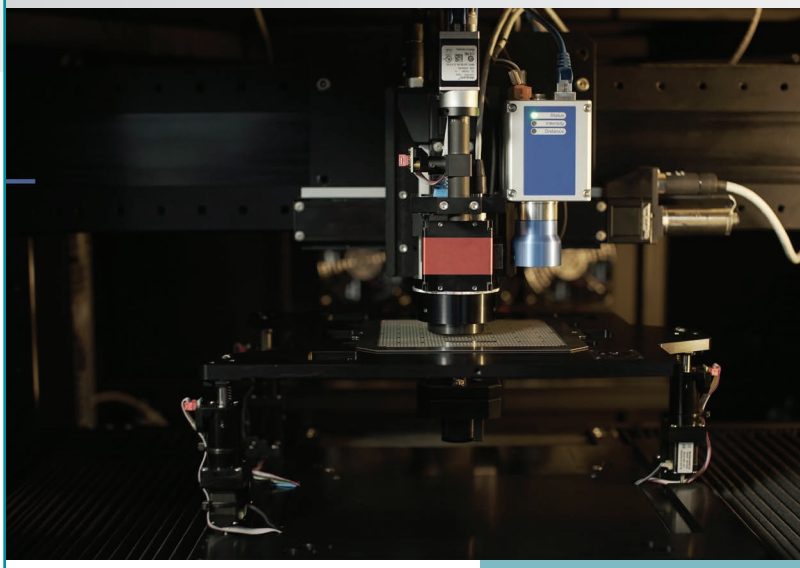
- Wide angle conoscope lens relay (enlarged FOV to 120° diagonal)
- Angular Resolution 0.25°
- 29Mpx camera, 14 bit depth
- Designed for 940 nm wavelenght
- Collimated laser beam with controlled diffraction optical system
- Wafer max dimension: 400mm-15.7inch
- Device scan time < 100 ms
- Device analysis time type < 1 sec
- Overall UPH > 3600

supernova tm
by alfamation

Unleash the Power of NI TestStand

SuperNova Test Application Framework for test sequence development and customization.

- Main sequence for fast testing cycle
- Modules for fast integration of tools and drivers
- Management of test diversities
- Ease of integration with database for result storage and analysis



alfamation tm

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